

<b>Notice of References Cited</b>	Application/Control No. 10/617,026	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Seokyun Moon	Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,211,851	04-2001	Lien et al.	345/89
*	B	US-6,873,313	03-2005	Washio et al.	345/100
*	C	US-2002/0149503	10-2002	Lautzenhiser, Lloyd L.	341/17
*	D	US-6,483,494	11-2002	Liaw et al.	345/92
*	E	US-2003/0038760	02-2003	Kim et al.	345/76
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.